

Shenzhen VSEEI Semiconductor Co., Ltd

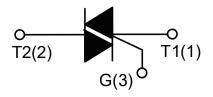
DESCRIPTION:

With high ability to withstand the shock loading of large current, T1610-600G series triacs provide high dv/dt rate with strong resistance to electromagnetic interface. With high commutation performances, 3 quadrants products especially recommended for use on inductive load.



MAIN FEATURES

Symbol	Value	Unit
I _{T(RMS)}	16	A
V _{DRM} /V _{RRM}	600/800/1200	V



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Storage junction temperature range	T _{stg}	-40-150	$^{\circ}$ C
Operating junction temperature range	Tj	-40-125	$^{\circ}$
Repetitive peak off-state voltage (T _j =25℃)	V _{DRM}	600/800/1200	V
Repetitive peak reverse voltage (T _j =25℃)	V _{RRM}	600/800/1200	V
Non repetitive surge peak Off-state voltage	V _{DSM}	V _{DRM} +100	V
Non repetitive peak reverse voltage	V _{RSM}	V _{RRM} +100	V
RMS on-state current TO-263 (Tc=80°C)	I _{T(RMS)}	16	А
Non repetitive surge peak on-state current (full cycle, F=50Hz)	Ітѕм	160	А
I ² t value for fusing (tp=10ms)	l ² t	128	A ² s
Critical rate of rise of on-state current (I _G =2×I _{GT})	dl/dt	50	A/µs
Peak gate current	I _{GM}	4	Α
Average gate power dissipation	P _{G(AV)}	1	W
Peak gate power	P _{GM}	5	W



ELECTRICAL CHARACTERISTICS (T_j =25 $^{\circ}$ C unless otherwise specified)

3 Quadrants

Cumbal	Test Condition	Quadrant		Value				Unit	
Symbol	rest Condition			BW	CW	sw	TW	Oilit	
Ідт	V 40V D 000	I - II -III	MAX	50	35	10	5	mA	
V _{GT}	V _D =12V R _L =33Ω	I - II -III	MAX	1.3				V	
V _{GD}	$V_D = V_{DRM} T_j = 125^{\circ}C$ $R_L = 3.3 K\Omega$	I - II -III	MIN		0.2	2		V	
,	1 401	I -III	MAX	70	50	30	15	mA	
IL	I _G =1.2I _{GT}	II	IVIAA	80 60		40	20	IIIA	
Ін	I _T =100mA		MAX	60	40	25	15	mA	
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	1000	500	200	100	V/µs	

4 Quadrants

Symbol	Test Condition	Quadrant		Va	Unit		
Symbol	rest Condition	Quaurant		В	С	Oilit	
I _{GT}		I - II -III	I - II -III MAX	50	25	mA	
IGI	V _D =12V R _L =33Ω	IV		70	50		
V _G T		ALL	MAX	1.5		V	
V _{GD}	$V_D = V_{DRM} T_j = 125^{\circ}C$ ALL $R_L = 3.3K\Omega$		MIN	0.2		V	
IL	I _G =1.2I _{GT}	I -III-IV	MAX	70	50	mA	
IL.		II	IVIAA	100	80	IIIA	
Ін	I _T =100mA		MAX	60	40	mA	
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	500	200	V/µs	

STATIC CHARACTERISTICS

Symbol	Parameter		V	I I sa i 4		
Symbol			-600V	-800V	-1200V	Unit
V_{TM}	I _{тм} =22.5A tp=380µs	Tj=25℃		1.5		V
I _{DRM}	V _D =V _{DRM} V _R =V _{RRM}	T _j =25℃	5	5	10	μA
I _{RRM}		T _j =125℃	1	1	2	mA



T1610-600G/BTA216B-600E/BTA316B-600E

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THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
R _{th(j-c)}	junction to case(AC)	TO-263	2.5	°C/W
R _{th(j-a)}	junction to ambient	10-203	45	C/VV



FIG.1 Maximum power dissipation versus RMS on-state current

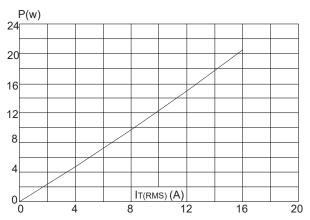


FIG.3: Surge peak on-state current versus number of cycles

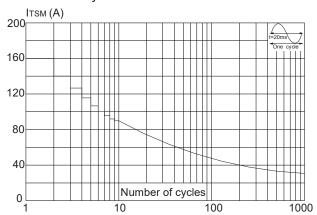


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of I²t (dI/dt < 50A/µs)

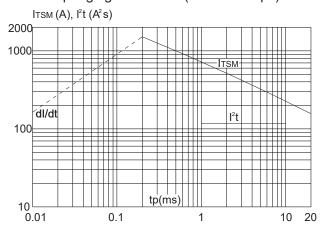


FIG.2: RMS on-state current versus ambient temperature(printed circuit board FR4, copper thickness:35µm)(full cycle)

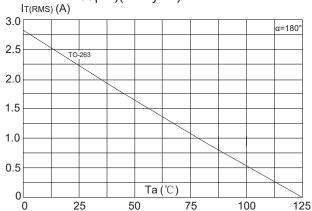


FIG.4: On-state characteristics (maximum values)

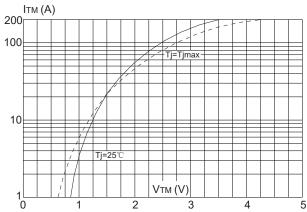
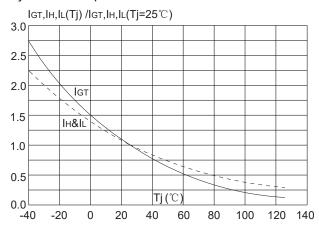


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature





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SOLDERING PARAMETERS

		1	
Reflow Condition		Pb-Free assembly	
		(see figure at right)	
	-Temperature Min	.450°C	
	(T _{s(min)})	+150℃	
Pre	-Temperature	.000°C	
Heat	Max(T _{s(max)})	+200℃	
	-Time (Min to Max) (ts)	60-180 secs.	
Average	ramp up rate	2°C/oop May	
(Liquidus	Temp (T∟)to peak)	3℃/sec. Max	
T _{s(max)} to	T _L - Ramp-up Rate	3°C/sec. Max	
	-Temperature(T _L)	+217℃	
Reflow	(Liquidus)	1217 0	
	-Temperature(t∟)	60-150 secs.	
Peak Ten	np (T _p)	+260(+0/-5)°C	
Time with	nin 5°Cof actual	20 40000	
Peak Temp (t _p)		20-40secs.	
Ramp-down Rate		6℃/sec. Max	
Time 25℃ to Peak Temp (T _P)		8 min. Max	
Do not ex	cceed	+260℃	

